

SON-2810

JPN  
Appl. No. 10/647,217



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Yoshitaka Kayukawa et al.

Confirmation No.: 1901

Application No.: 10/647,217

Art Unit: 2811

Filed: August 26, 2003

Examiner: Violet McCoy

For: SEMICONDUCTOR INTEGRATED CIRCUIT  
AND METHOD FOR TESTING SAME

**STATUS INQUIRY**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. Specifically, please advise us of when an initial Office Action on the merits may be expected from the Patent and Trademark Office. The application has now been pending approximately 18 months without an action on the merits.

Dated: February 25, 2005

Respectfully submitted,

By \_\_\_\_\_

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